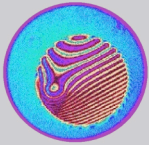


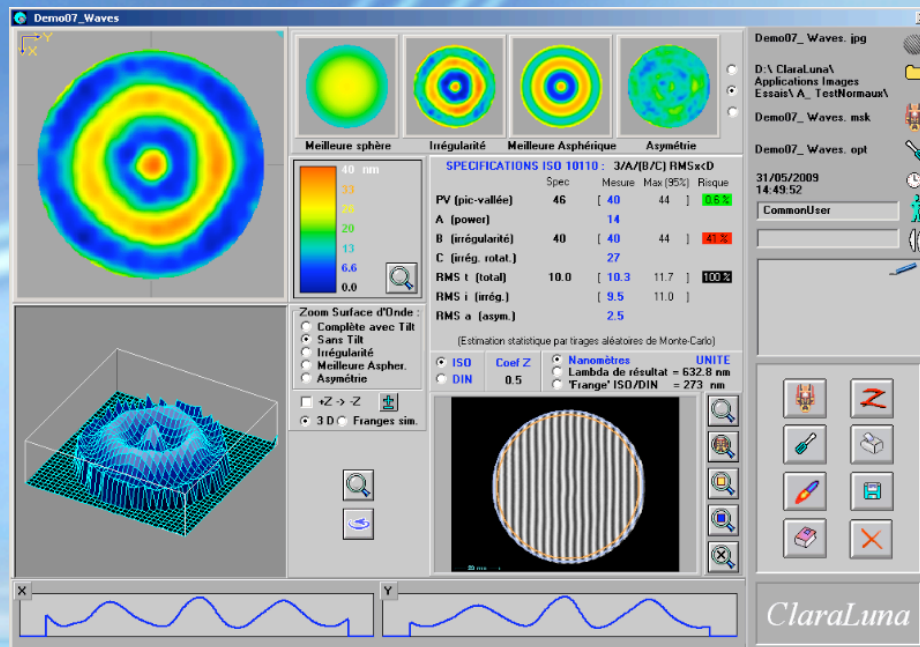
ClaraLuna

Interferometry software



ClaraLuna

Production
and Quality
Oriented

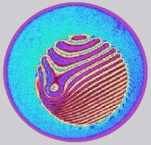


High
performances

Low-cost

Section 1

Production and Quality Oriented



ClaraLuna

Production and Quality Oriented

Levels of use

Advanced

Easy

Basic

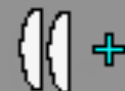
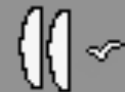
Production

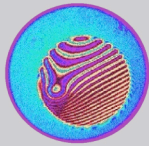
User

CommonUser

Mode

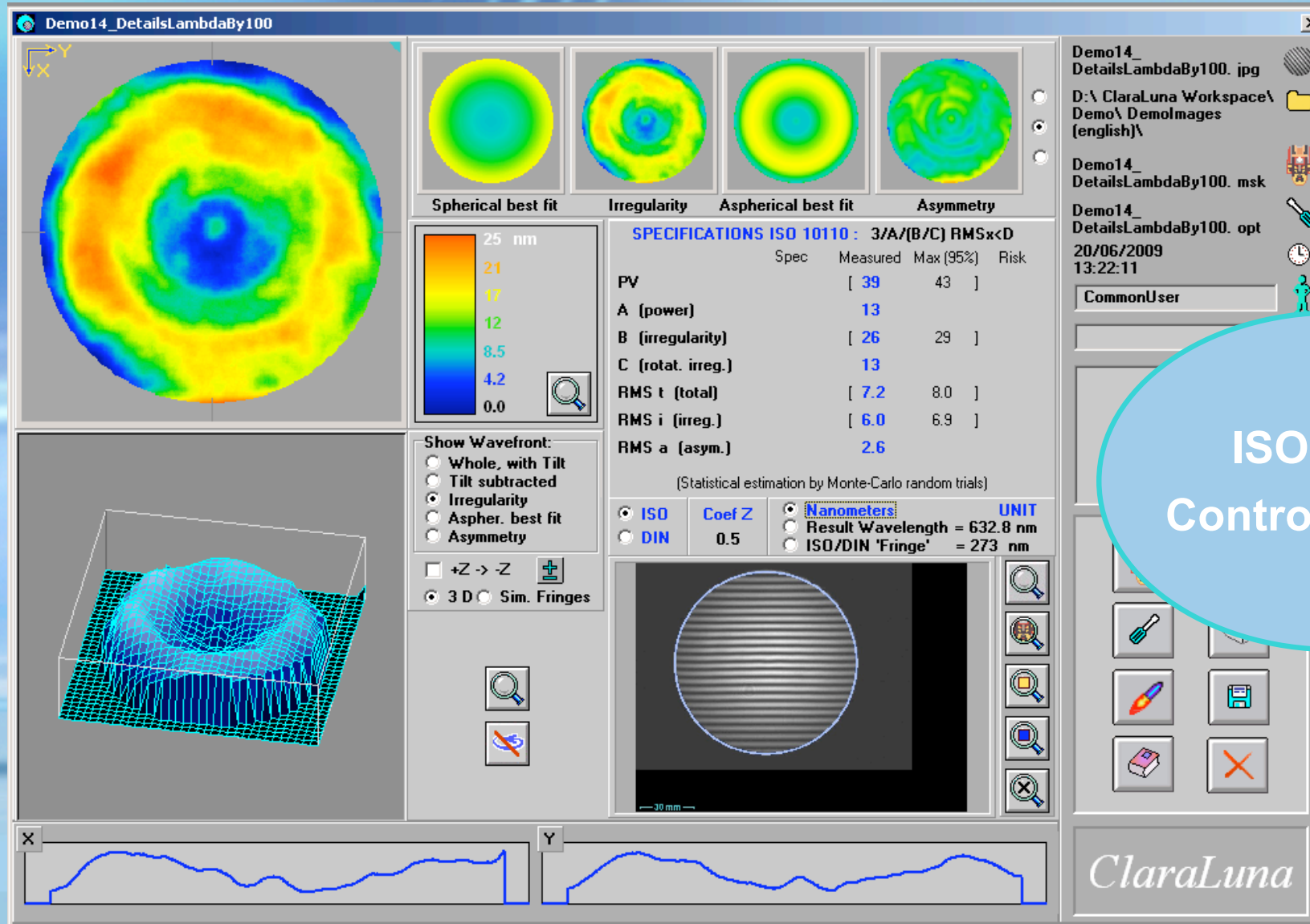
Regular

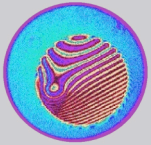




ClaraLuna

Production and Quality Oriented





ClaraLuna

Production and Quality Oriented

ISO specification

Measured value

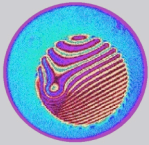
Risk to be out of tolerance

ISO 10110 SPECIFICATIONS : 3/A/(B/C) RMSx<D

	Spec	Measured	Max (95%)	Risk
PV (peak-valley)	40	[34 38]		0.5%
A (power)		2		
B (irregularity)	37	[34 38]		9%
C (rot. irreg.)		2		
RMS t (total)	6.0	[6.0 6.5]		30%
RMS i (irreg.)	5.0	[5.9 6.4]		100%
RMS a (asym.)		5.1		

Visualising the risk by color code

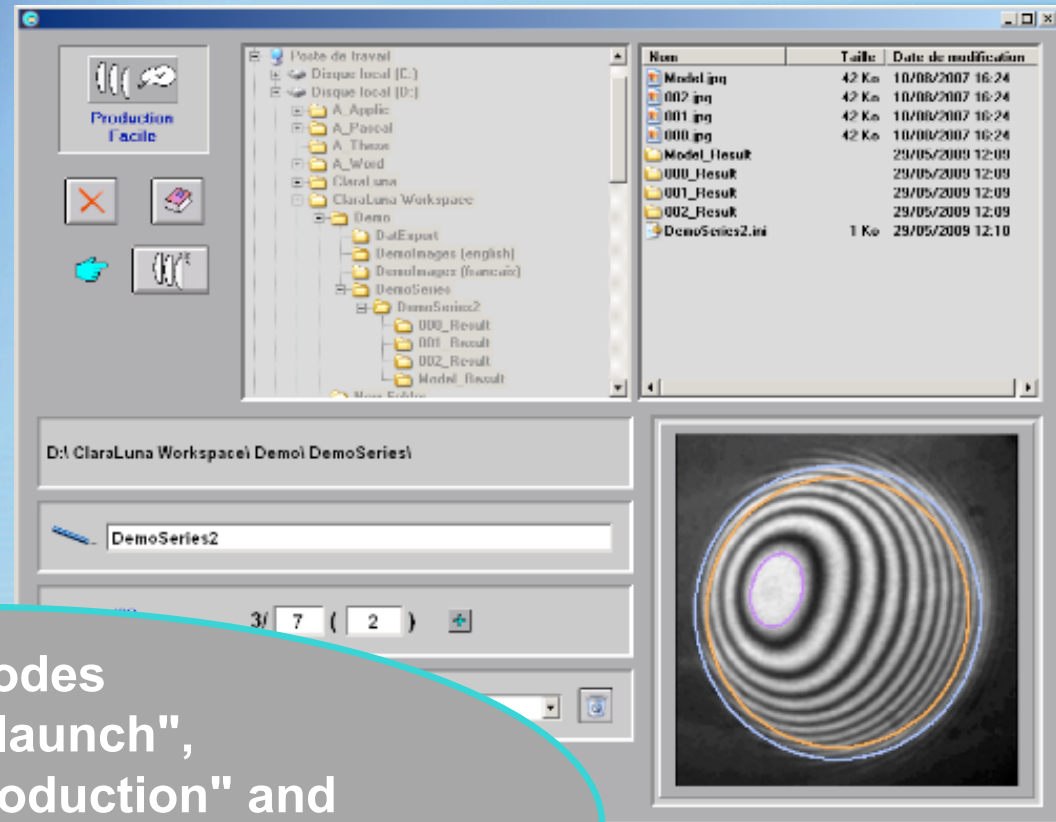
Upper bound of 95 % confidence interval



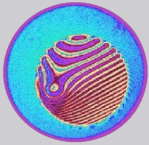
ClaraLuna

Production and Quality Oriented

User-friendly
interfaces



With Modes
"Grab and launch",
"Easy", "Easy Production" and
"Advanced Production", ClaraLuna
is highly easy and pleasant
to use



ClaraLuna

Traceability - Quality control Production Oriented

Production Mode

Series of components



UNIT

- Nanometers
- λ 632.8 nm
- Fringe 273 nm

Series = 2008-11-17

Customer part name	ISO results (Unit= ISO Fringe 273 nm)				DIN results (Unit=Fr...			
	PV	A (pow)	B (irr)	C (asy)	RMS tot	RMS irr	RMS asy	
	0.73				0.37			
006 / ess_003	0.88	0.53	0.63	0.12	0.21	0.08	0.07	0.3
010 / ess_004	1.37	0.82	0.90	0.22	0.32	0.14	0.11	0.5
013 / ess_005	3.85	0.32	3.83	0.32	0.62	0.53	0.51	0.5
023 / ess_007	0.69	0.11	0.68	0.09	0.13	0.12	0.11	0.3
024	0.64	0.02				0.13	0.10	0.3
025 / ess_009	0.63					0.10	0.2	0.3
026 / ess_010	0.7						0.3	0.4
027 / ess_011							1.1	1.5
028 / ess_012							0.3	0.4
Test2_23-29_000 / ess_013	0.3						0.2	0.3
Test2_23-29_001 / ess_014	0.37					0.07	0.2	0.3
Test2_23-29_002 / ess_015	0.37	0.05				0.07	0.06	0.1
Test2_23-29_003 / ess_016	4.66	0.38	4.38	0.18	0.73	0.69	0.68	1.3
Test2_23-29_004 / ess_017	0.40	0.18	0.33	0.08	0.10	0.07	0.06	0.1
Test2_23-29_005 / ess_018	0.45	0.22	0.35	0.07	0.11	0.07	0.06	0.2
Test2_23-29_006 / ess_019	0.51	0.25	0.41	0.06	0.12	0.07	0.06	0.2
Test2_23-29_007 / ess_020	1.211	0.215	1.124	0.095	0.220	0.180	0.170	0.40
Test2_23-29_008 / ess_021	1.4058	0.1873	1.3662	0.0616	0.2046	0.1981	0.1980	0.347

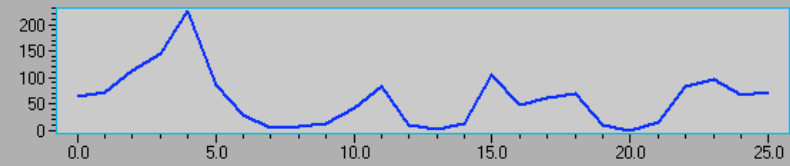
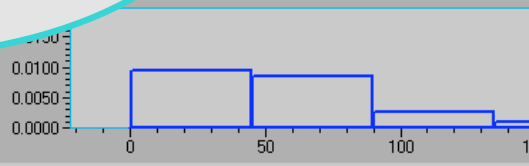
Synopsis of ISO - DIN results

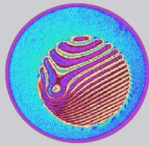
Part automatic naming and numbering with customizable format

Histogram

A (power)

Time series





ClaraLuna

Traceability - Quality control Production Oriented

Production Mode

Series of components

Series = 2008-11-17

Customer part name	ISO results (Unit= ISO Fringe 273 nm)				DIN results (Unit=Fr)				DIN results (Unit=Fr)			
	PV	A (pow)	B (irr)	C (asy)	RMS tot	RMS irr	RMS asy					
006 / ess_003	0.88	0.53	0.63	0.12	0.21	0.08	0.07	0.3				
010 / ess_004	1.37	0.82	0.90	0.22	0.32	0.14	0.11	0.5	0.2			
013 / ess_005	3.85	0.32	3.83	0.32	0.62	0.53	0.51	0.5	0.9	4.07	0	
023 / ess_007	0.69	0.11	0.68	0.09	0.13	0.12	0.11	0.3	0.5	0.36	0	
024	0.64	0.02	0.65	0.06	0.13	0.13	0.10	0.3	0.6	0.39	0	
	0.63	0.02	0.62	0.06	0.12	0.10	0.10	0.2	0.3	0.37	0	
	0.04	0.71	0.14	0.13	0.11	0.10	0.3	0.4	0.49	0		
		1.87	0.09	0.45	0.43	0.43	1.1	1.5	1.78	0		
		1.56	0.09	0.15	0.10	0.09	0.3	0.4	0.41	0		
		0.37	0.06	0.08	0.07	0.07	0.2	0.3	0.20	0		
		0.37	0.05	0.08	0.07	0.07	0.2	0.3	0.19	0		
		0.36	0.06	0.08	0.07	0.06	0.1	0.2	0.18	0		
		0.38	4.38	0.18	0.73	0.69	0.68	1.3	2.0	3.87	0	
ess_017	0.40	0.18	0.33	0.08	0.10	0.07	0.06	0.1	0.3	0.20	0	
ess_018	0.45	0.22	0.35	0.07	0.11	0.07	0.06	0.2	0.3	0.24	0	
ess_019	0.51	0.25	0.41	0.06	0.12	0.07	0.06	0.2	0.3	0.31	0	
	1.211	0.215	1.124	0.095	0.220	0.180	0.170					
	1.4058	0.1873	1.3662	0.0616	0.2046	0.1981						

Recall ISO-DIN control reports

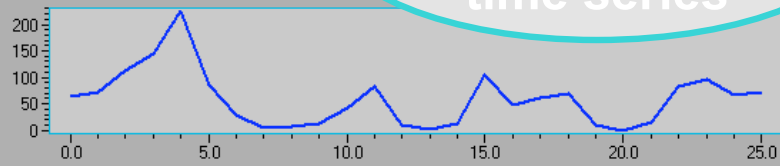
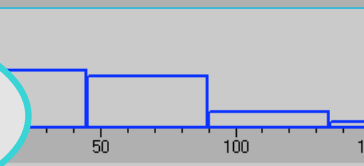
ISO-DIN parameters time series

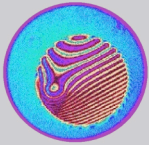
Histograms

Histogram

A (power)

Time series





ClaraLuna

Traceability - Quality control Production Oriented

Assistant for
diffraction
gratings
metrology

Defining masks and
acquiring interferograms
are guided by an
assistant

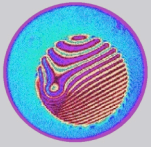
Computing
automatically realigns
masks, averages wavefronts
having same order and tilt,
and does the final linear
combination

Working folder,
masks, settings,
interferograms, results:
Everything is saved,
checkable, reusable.

The screenshot displays the ClaraLuna software interface. At the top, there is a file explorer showing a directory structure for 'DemoReseau1' with subfolders for '000_Result' through '009_Result'. Below the file explorer is a control panel with various icons and buttons. A central window shows a list of files with columns for 'Nom', 'Taille', and 'Type'. The files listed include 'ClaraLuna', 'ess_Image-1', 'ess_Image+1-1', 'gr_Image+1+1_000.jpg', 'grrr_Image-1-1_000.jpg', 'grrr_Image+1-1_000.jpg', 'Image+1+1_000.jpg', 'Model-1-1.jpg', 'Model-1-1.msk', 'Model-1-1_FringesMask.jpg', 'Model-1+1.jpg', 'Model-1+1.msk', and 'Model-1+1_FringesMask.jpg'. Below the file list, there is a 'Choose result name' section with a dropdown menu set to 'Grating_000_001...'. A table of settings is visible, including '2: Order +1 Tilt +1', '3: Order +1 Tilt -1', and 'Order -1 Tilt +1'. A 'Coeffs' section shows values of '+0.5' and '-0.5'. A preview window on the right shows a diffraction grating pattern with the caption 'Grating_067_Image-1-1_001.jpg'. At the bottom, there is a 'Launch computation' button and a 'Finger wave resolution' section.

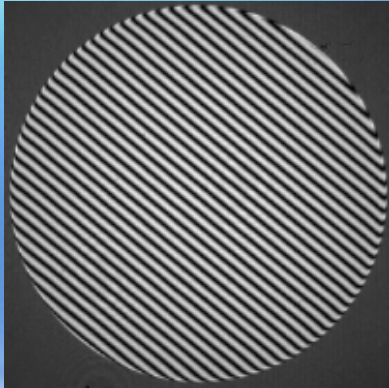
Section 2

Technical performances

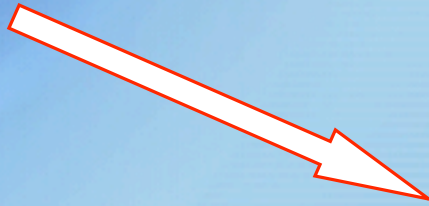


ClaraLuna

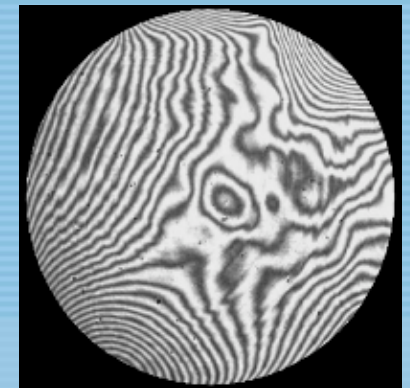
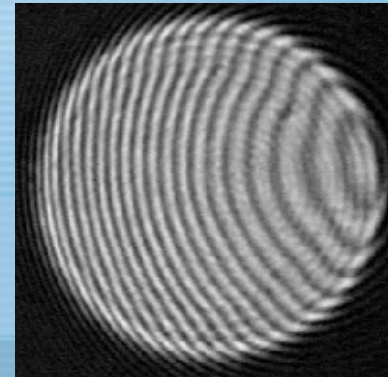
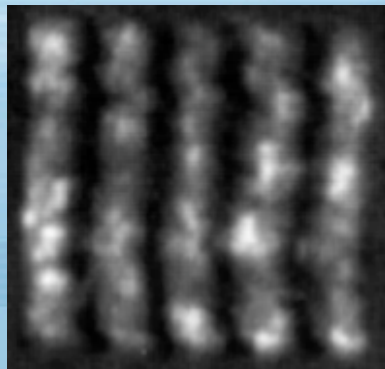
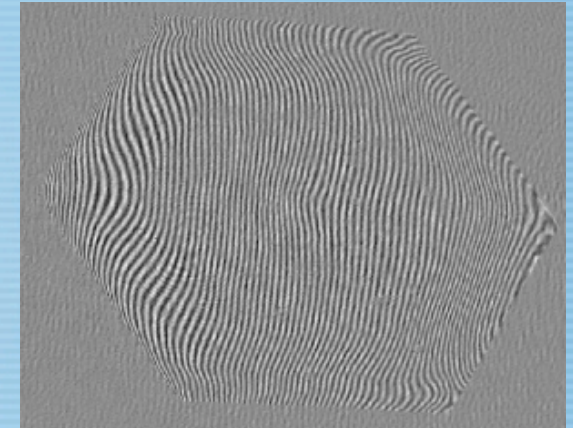
covers the whole range of situations
in optical components metrology

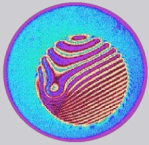


very high
precision
and
resolution



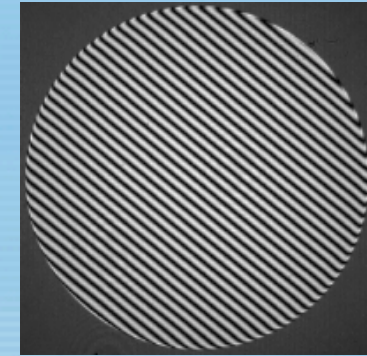
very high
robustness





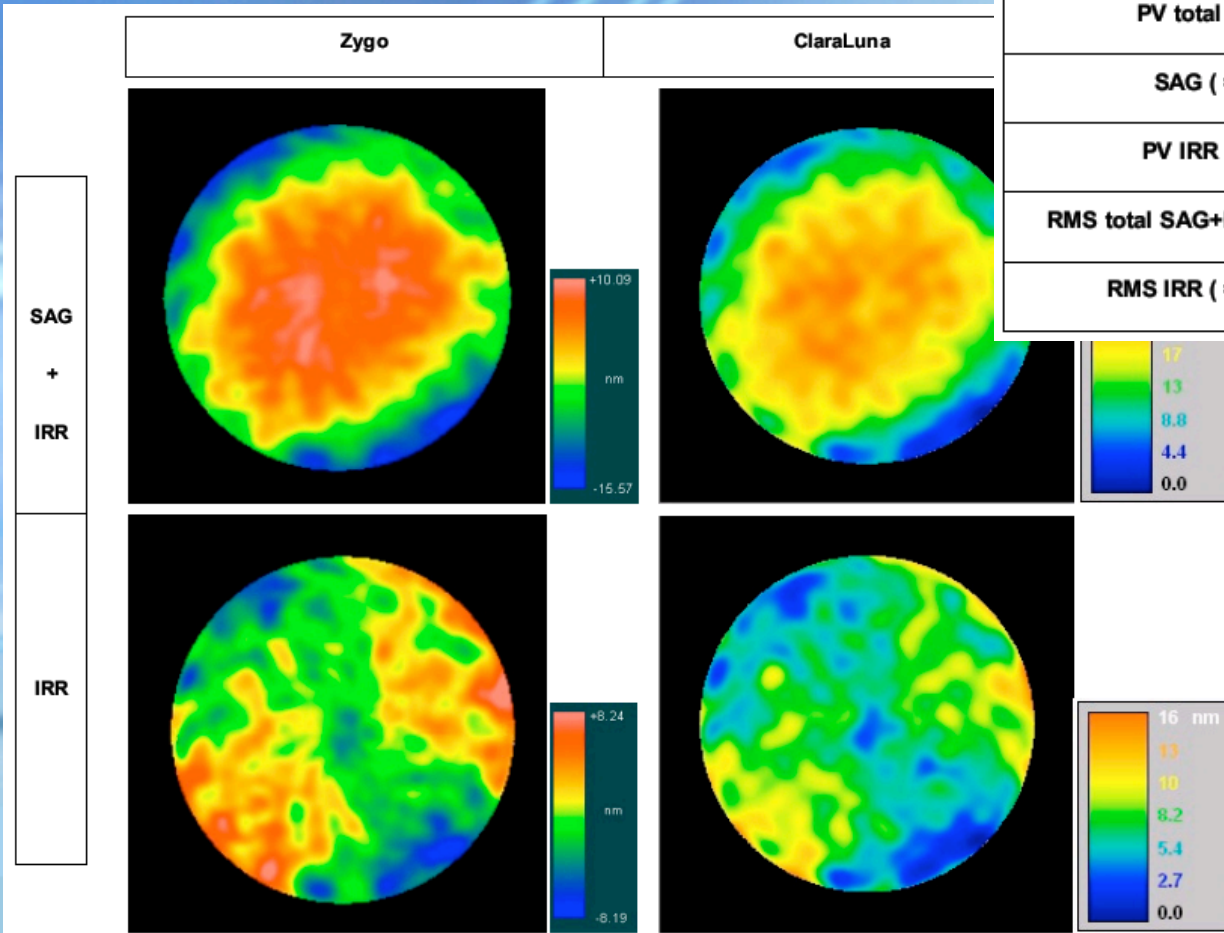
ClaraLuna

Very high precision

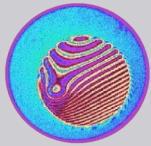


Comparing ClaraLuna vs Zygo :
 $\lambda/100$ rms part

(nanometers)	Zygo	ClaraLuna
PV total SAG+IRR	25.6	26.0
SAG (=ISO A)	18.6	17.8
PV IRR (=ISO B)	16.4	15.0
RMS total SAG+IRR (=ISO Rms t)	6.0	6.1
RMS IRR (=ISO Rms i)	2.6	2.6



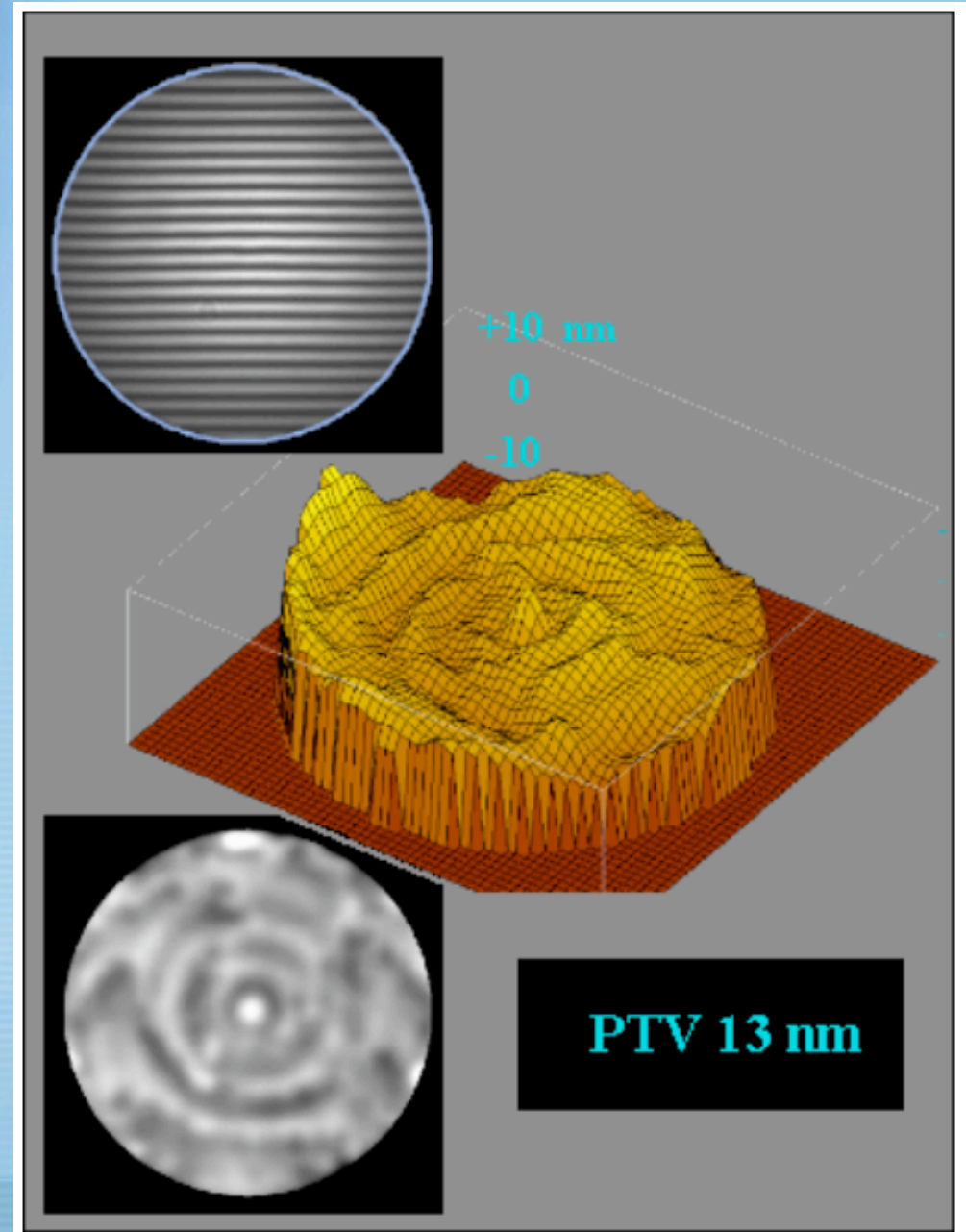
With suitable measuring conditions, ClaraLuna shows both a precision and a resolution close to that of a phase shifting device and software

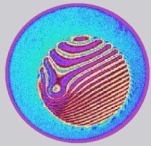


ClaraLuna

ClaraLuna can
read details with λ
/100 amplitude

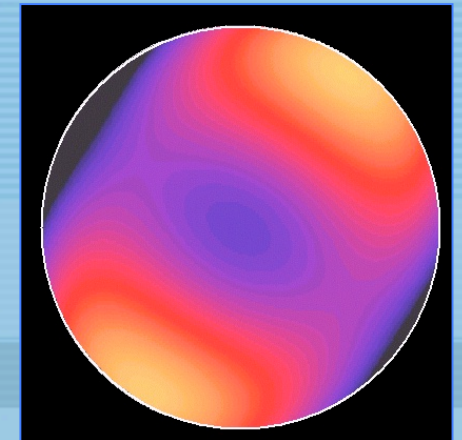
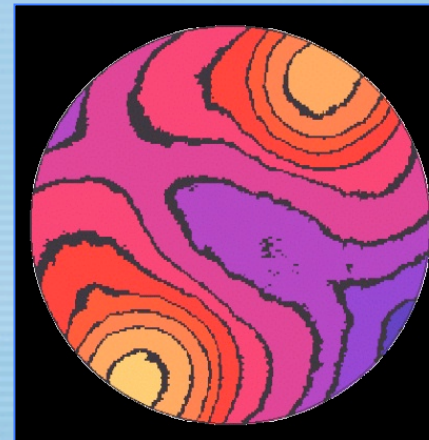
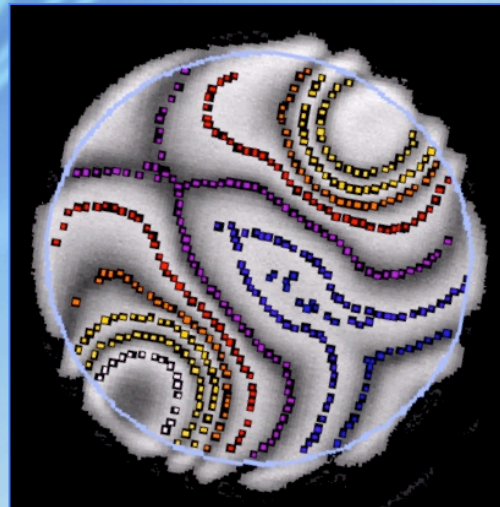
Its resolution is
nanometric



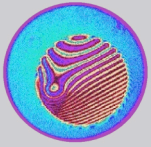


ClaraLuna

High robustness in tricky cases

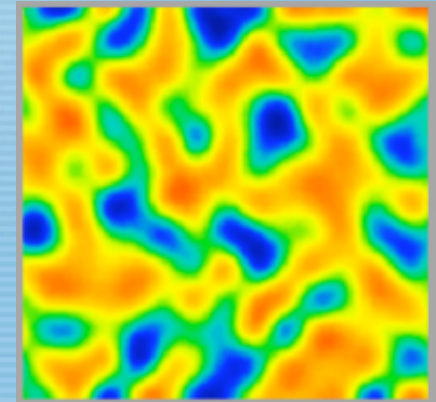
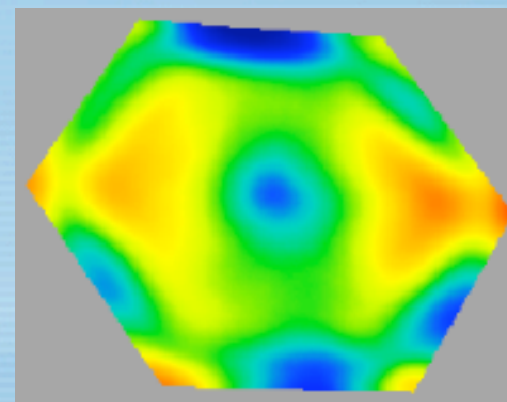
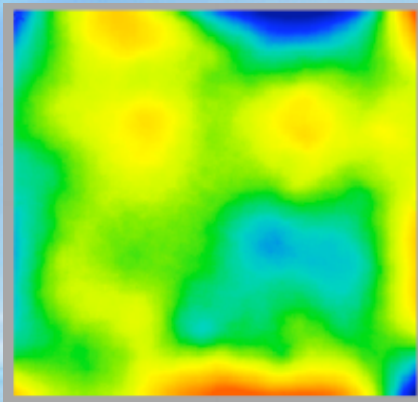
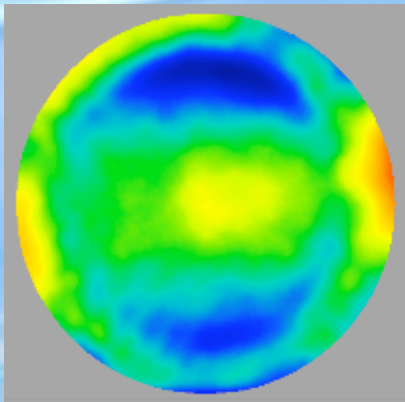
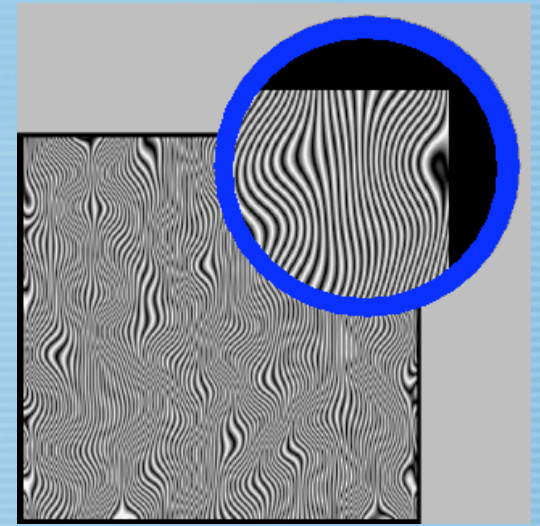
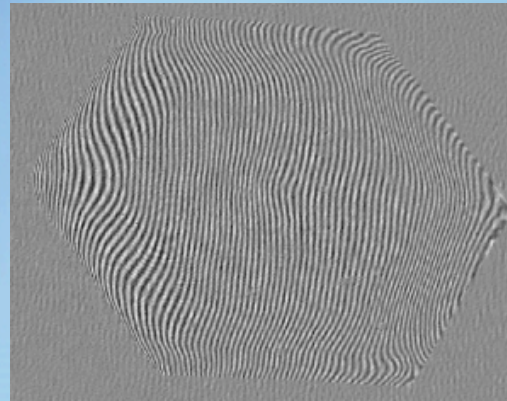
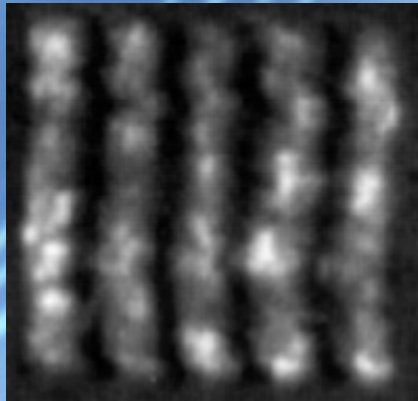
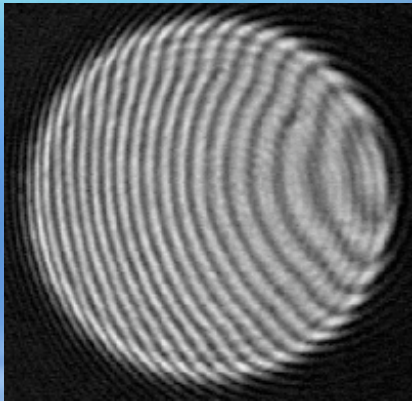


strongly deformed components,
closed fringes

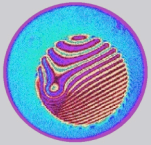


ClaraLuna

High robustness in tricky cases



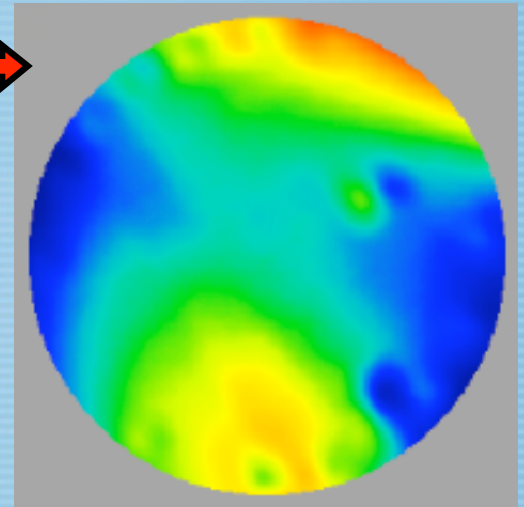
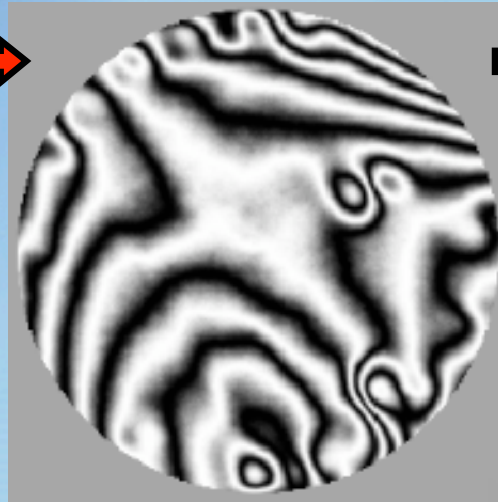
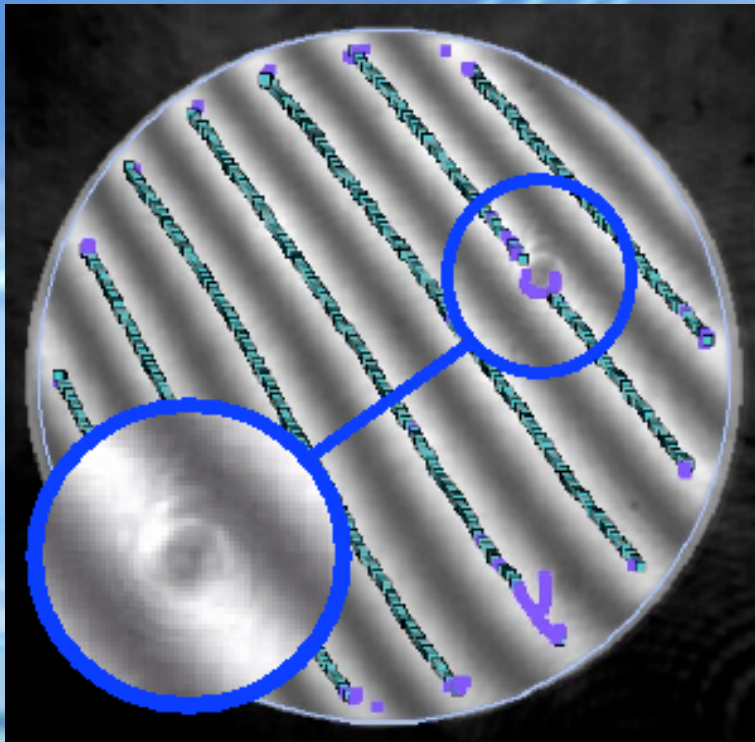
noisy or broken fringes, low contrast, vibrations, air turbulence,
very high or very low number of fringes...



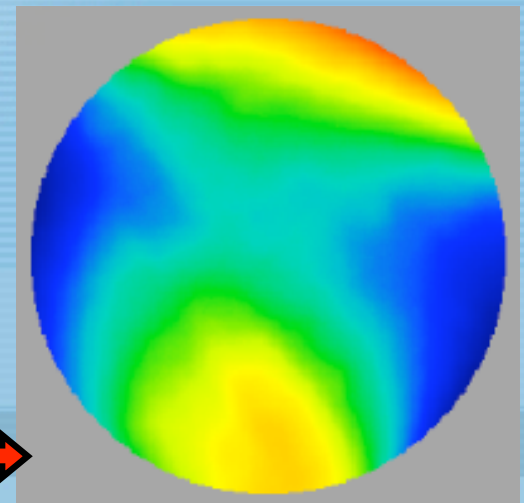
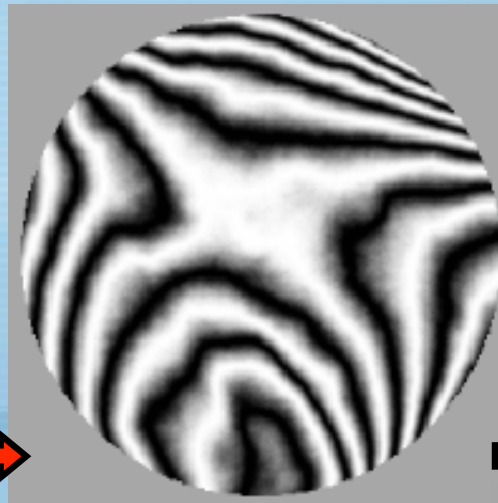
ClaraLuna

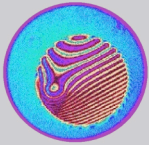
High robustness with respect to noise

aberrant data



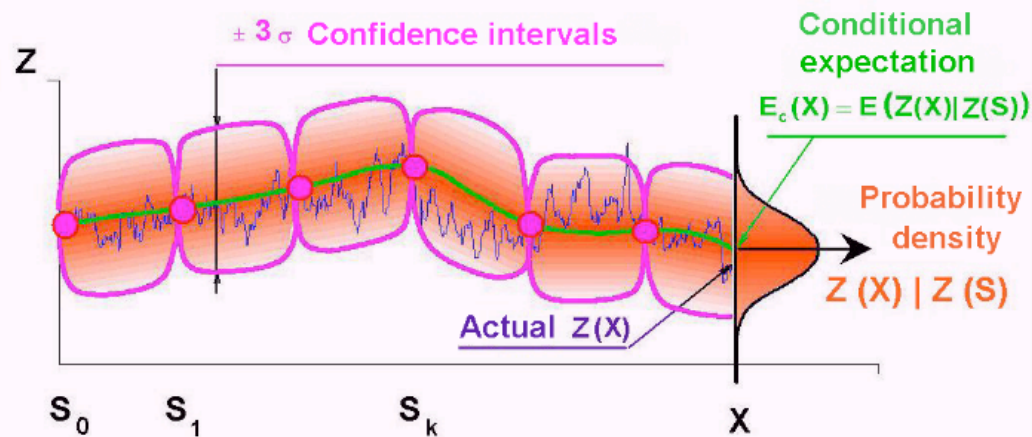
detection and correction





ClaraLuna

The main algorithms are novel worldwide

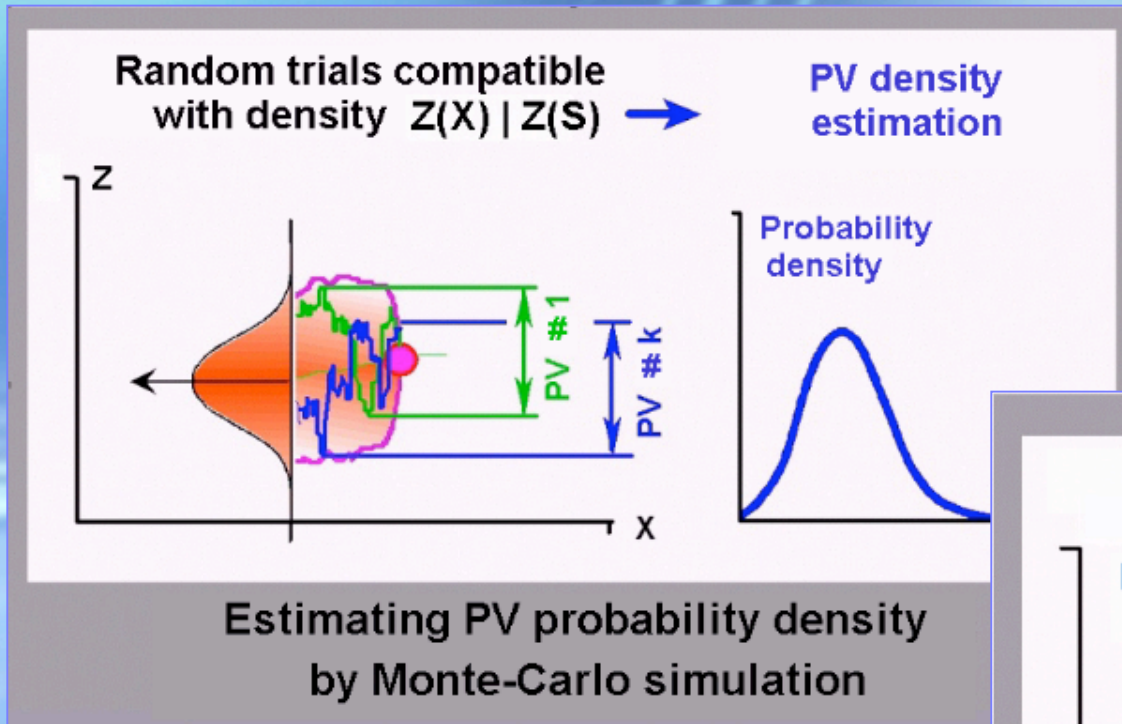
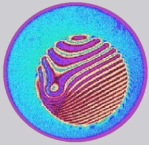


Linear Prediction
of a Random Function

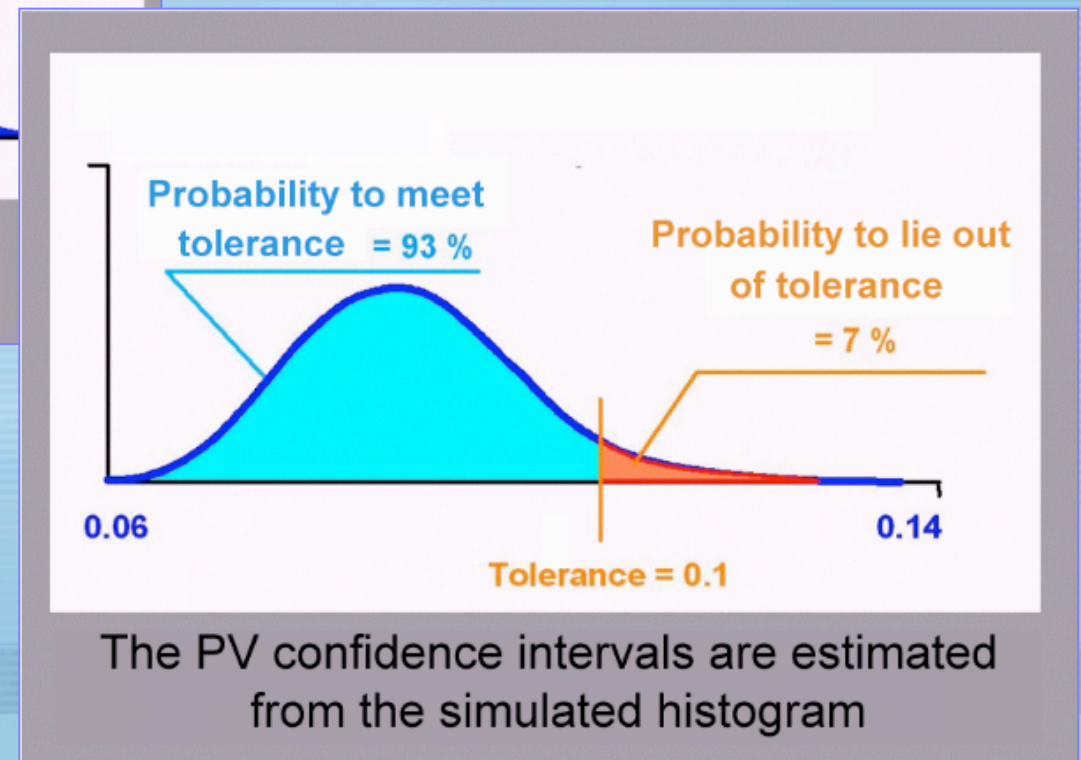
→ Extracting **all information**
contained in the data

Statistical
optimisation by linear
prediction :

Reconstucting
the unknown data
by its
most probable
position
with respect to
known data



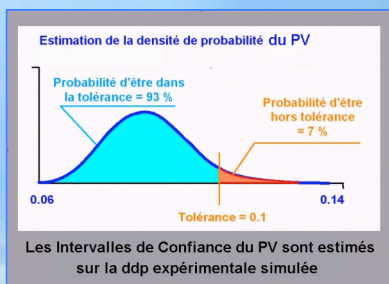
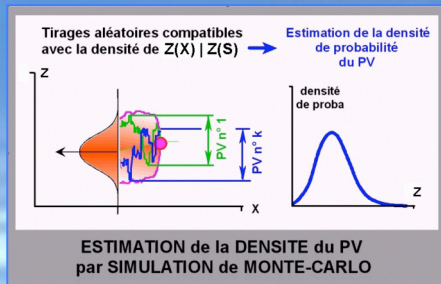
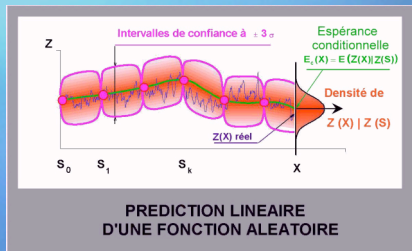
estimating PV and RMS confidence intervals



estimating the risk = probability to be out of tolerance for :

- rms, ptv of phase
- rms, ptv of slopes

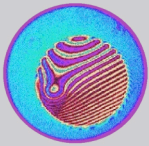
The main algorithms are novel worldwide



ISO 10110 SPECIFICATIONS : 3/A/(B/C) RMSx<D

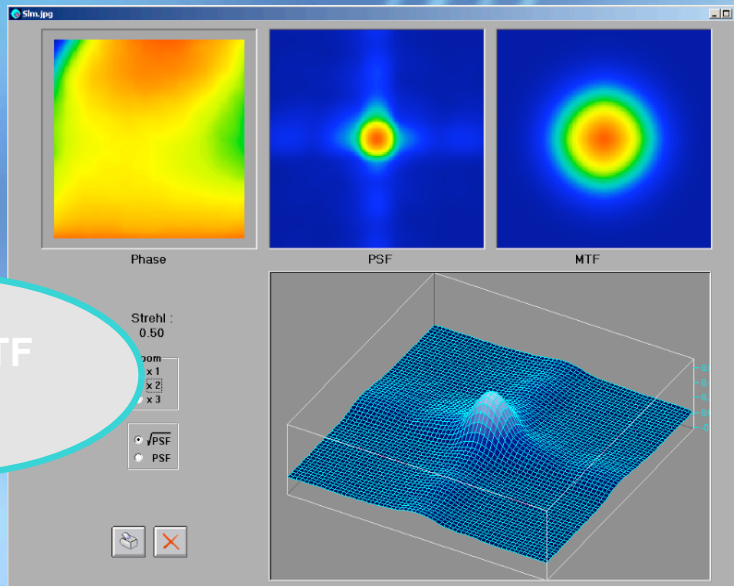
	Spec	Measured	Max (95%)	Risk
PV (peak-valley)	40	[34 38]		0.5 %
A (power)		2		
B (irregularity)	37	[34 38]		9 %
C (rot. irreg.)		2		
RMS t (total)	6.0	[6.0 6.5]		30 %
RMS i (irreg.)	5.0	[5.9 6.4]		100 %
RMS a (asym.)		5.1		

ClaraLuna is the unique software for optical components metrology providing the uncertainty of results and the risk to be out of tolerance

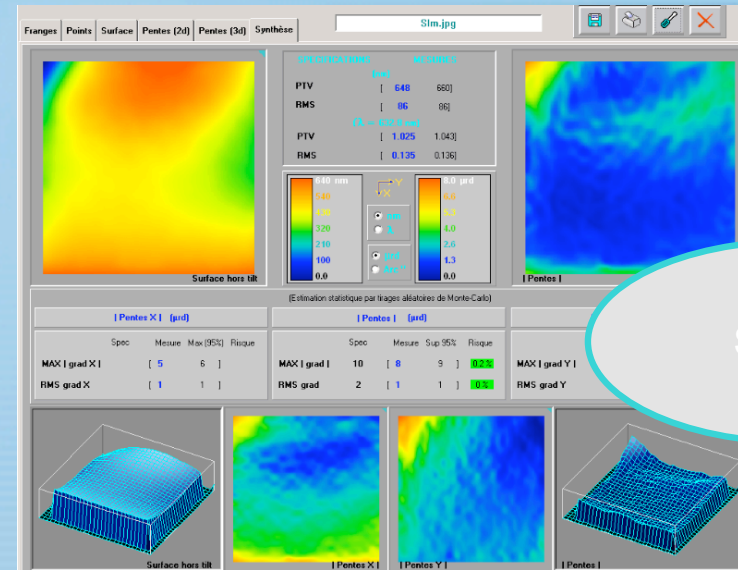


ClaraLuna

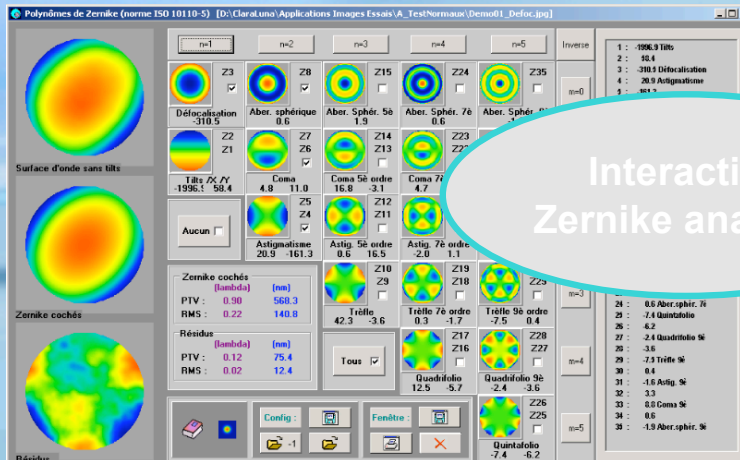
Classic analysis tools, easy and comfortable to use and read



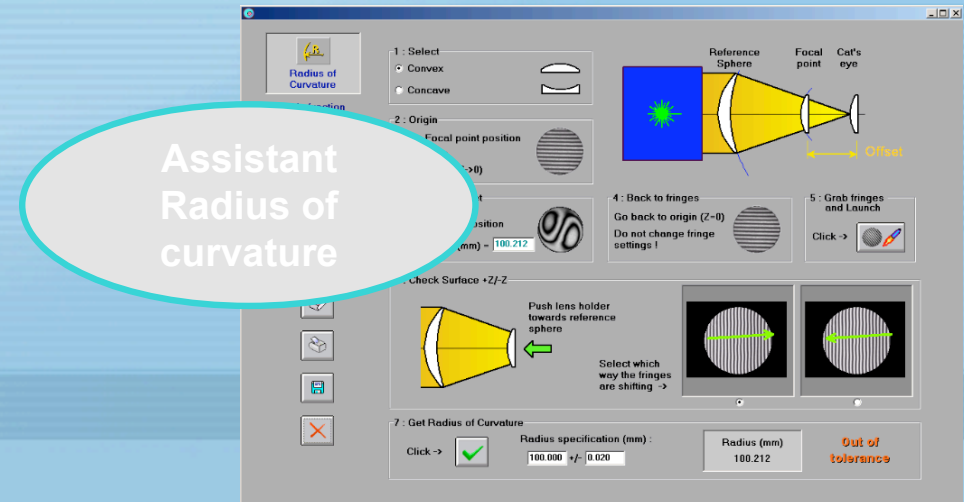
PSF – MTF
Strehl



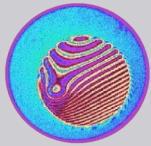
Slopes



Interactive
Zernike analysis



Assistant
Radius of
curvature



ClaraLuna

Industrial references

OPTICO
AG

angēnieux

**Optique
Maris-Delfour**



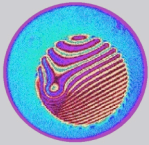
BM Optik

SPANOPTIC



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Industrial references

ASM: a scaled down Active Segmented Mirror for the Active Phasing Experiment

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München, Germany

ABSTRACT

The construction of extremely large telescope is only possible with a segmented primary mirror. The phasing of the primary mirror due to its size and its number of segments is a main concern at the European Southern Observatory. The European Southern Observatory has developed a test bench called Active Phasing Experiment to study new phasing technology and new telescope control system. The key subsystem of this experiment is a scaled down Active Segmented Mirror (ASM) composed of sixty-one hexagonal segments of seventeen millimeters side to side. Each hexagonal mirror can all be controlled in piston, tip and tilt. The integration of this jewel piece of opto-mechanic started after the successful results obtained with the manufacturing of a prototype composed of only seven modules.

Keywords: ESO, ASM, APE, ELT, hexagonal segments, development, scaled down, active optics, ClaraLuna.

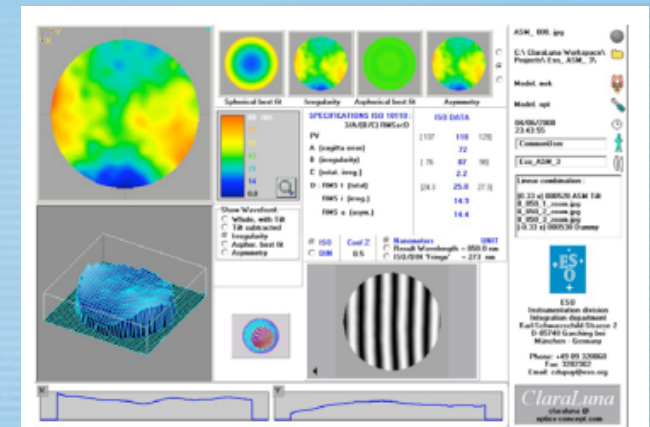
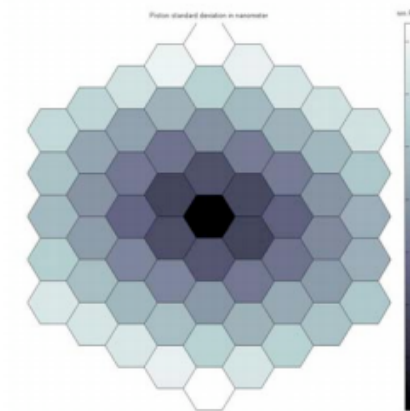


Figure 24 : ASM surface error after phasing



ESO Instrumentation Division used ClaraLuna to qualify the ASM (prototype of primary segmented for the future ELT)



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